Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/810,574	LEE, BYUNG-PYLL		
Examiner	Art Unit		
Hau V. Phan	3618		

	SEAR	CHED	
Class	Subclass	Date	Examiner
280	163 164.1 164.2	8/12/2006	HP
	759		
	782		
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296	193.12	8/12/2006	HP
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429	100	8/12/2006	HP

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Text Search	8/12/2006	HP		